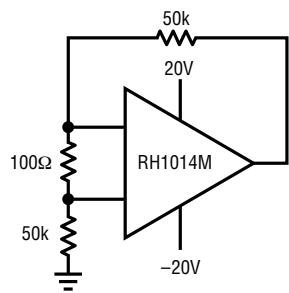


DESCRIPTION

The RH1014M is the first precision quad operational amplifier which directly upgrades designs in the industry standard 8-pin DIP LM124/LM148/OP-11/5156 pin configuration. Low offset voltage ($300\mu V$ max), low drift ($\leq 2.5\mu V/{^\circ}C$), low offset current ($\leq 1.5nA$), and high gain (1.2 million min) combine to make the RH1014M four truly precision amplifiers in one package.

The wafer lots are processed to Linear Technology's in-house Class S flow to yield circuits usable in stringent military applications.

BURN-IN CIRCUIT



RH1014M BI

ABSOLUTE MAXIMUM RATINGS

Supply Voltage	$\pm 22V$
Differential Input Voltage	$\pm 30V$
Input Voltage	Equal to Positive Supply Voltage 5V Below Negative Supply Voltage
Output Short-Circuit Duration	Indefinite
Operating Temperature Range	-55°C to 125°C
Storage Temperature Range	-65°C to 150°C
Lead Temperature (Soldering, 10 sec)	300°C

 LTC and LT are registered trademarks of Linear Technology Corporation.

PACKAGE INFORMATION

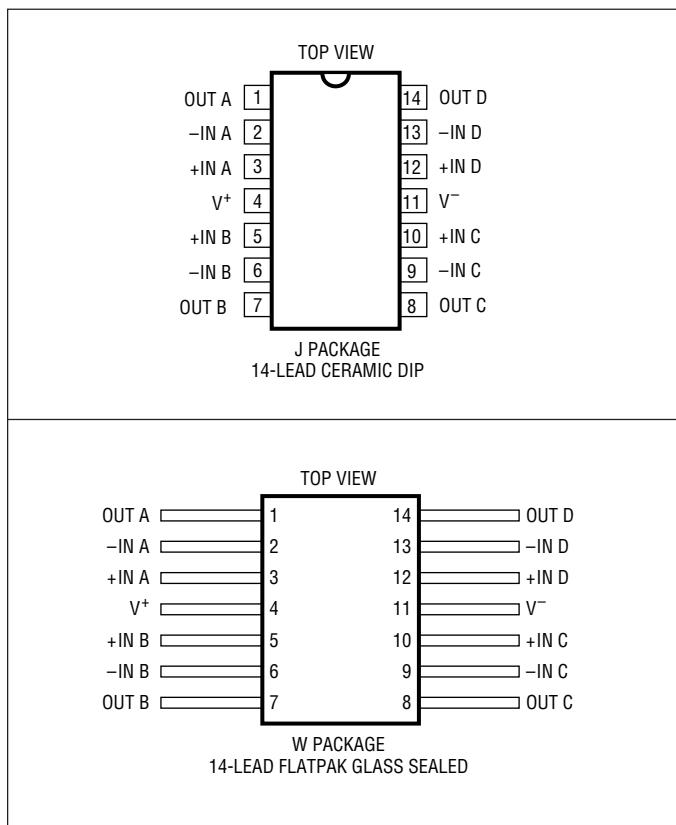


TABLE 1: ELECTRICAL CHARACTERISTICS (Pre-Irradiation) $V_S = \pm 15V$, $V_{CM} = 0V$, unless otherwise noted.

SYMBOL	PARAMETER	CONDITIONS	NOTES	TA = 25°C			SUB-GROUP	-55°C ≤ TA ≤ 125°C			SUB-GROUP	UNITS
				MIN	TYP	MAX		MIN	TYP	MAX		
V _{OS}	Input Offset Voltage				300	1			550	2,3		μV
			2		450	1						μV
		V _{CM} = 0.1V	2						750	2		μV
$\frac{\Delta V_{OS}}{\Delta T_{Temp}}$	Average Tempco of Offset Voltage		1						2.5			μV/°C
$\frac{\Delta V_{OS}}{\Delta T_{Time}}$	Long Term V _{OS} Stability				0.5							μV/Mo
I _{OS}	Input Offset Current				10	1		20	20	2,3		nA
			2		10	1		20	20	2,3		nA
I _B	Input Bias Current				30	1		45	45	2,3		nA
			2		50	1		120	120	2,3		nA
e _n	Input Noise Voltage	0.1Hz to 10Hz			0.55							μV _{P-P}
	Input Noise Voltage	f ₀ = 10Hz			24							nV/√Hz
	Density	f ₀ = 1000Hz			22							nV/√Hz
i _n	Input Noise Current Density	f ₀ = 10Hz			0.07							pA/√Hz
R _{IN}	Input Resistance	Differential	1	70								MΩ
		Common Mode		4								GΩ
A _{VOL}	Large-Signal Voltage Gain	V ₀ = ±10V, R _L ≥ 2k		1.2		4	0.25		5,6			V/μV
		V ₀ = ±10V, R _L ≥ 600Ω		0.5		4						V/μV
		V ₀ = 5mV to 4V, R _L = 500Ω	2	1								V/μV
	Input Voltage Range		1	13.5								V
			1	-15.0								V
			1,2	3.5								V
			1,2	0								V
CMRR	Common-Mode Rejection Ratio	V _{CM} = 13.5V, -15V		97		1						dB
		V _{CM} = 13V, -14.9V					94		2,3			dB
PSRR	Power Supply Rejection Ratio	V _S = ±2V to ±18V		100		1	97		2,3			dB
	Channel Separation	V ₀ = ±10V, R _L = 2k		120		1						dB
V _{OUT}	Output Voltage Swing	R _L ≥ 2k		±12.5		4	±11.5		5,6			V
		Output Low, No Load	2	25	4							mV
		Output Low, 600Ω to GND	2	10	4		18		5,6			mV
		Output Low, I _{SINK} = 1mA	2	350	4							mV
		Output High, No Load	2	4.0	4							V
		Output High, 600Ω to GND	2	3.4	4	3.1			5,6			V
SR	Slew Rate			0.2		4						V/μs
I _S	Supply Current	Per Amplifier		0.55	1		0.70		2,3			mA
			2	0.50	1		0.65		2,3			mA

TABLE 1A: ELECTRICAL CHARACTERISTICS (Post-Irradiation) $V_S = \pm 15V$, $V_{CM} = 0V$, $T_A = 25^\circ C$, unless otherwise noted.

SYMBOL	PARAMETER	CONDITIONS	NOTES	10KRAD(Si) MIN	10KRAD(Si) MAX	20KRAD(Si) MIN	20KRAD(Si) MAX	50KRAD(Si) MIN	50KRAD(Si) MAX	100KRAD(Si) MIN	100KRAD(Si) MAX	200KRAD(Si) MIN	200KRAD(Si) MAX	UNITS
V_{OS}	Input Offset Voltage			450		450		600		750		900		μV
			2	600		600		750		900				μV
I_{OS}	Input Offset Current			10		10		15		20		25		nA
			2	10		10		15		20				nA
I_B	Input Bias Current			60		75		100		175		250		nA
			2	80		100		125		200				nA
	Input Voltage Range		1	13.5		13.5		13.5		13.5		13.5		V
			1	-15.0		-15.0		-15.0		-15.0		-15.0		V
			2	3.5		3.5		3.5		3.5				V
			2	0		0		0		0				V
CMRR	Common-Mode Rejection Ratio	$V_{CM} = 13V, -15V$		97		97		94		90		86		dB
PSRR	Power Supply Rejection Ratio	$V_S = \pm 10V$ to $\pm 18V$		100		98		94		86		80		dB
A_{VOL}	Large-Signal Voltage Gain	$R_L \geq 10k$, $V_0 = \pm 10V$		500		200		100		50		25		V/mV
V_{OUT}	Maximum Output Voltage Swing	$R_L \geq 10k$		± 12.5		± 12.5		± 12.5		± 12.5		± 12.5		V
		Output Low, No Load	2	25		30		40		50				mV
		Output Low, 600Ω to GND	2	10		10		10		10				mV
		Output Low, $I_{SINK} = 1mA$	2	0.6		0.8		1.0		1.6				V
		Output High, No Load	2	4.0		4.0		4.0		4.0				V
		Output High, 600Ω to GND	2	3.4		3.2		3.0		2.8				V
SR	Slew Rate	$R_L \geq 10k$		0.13		0.12		0.11		0.07		0.01		$V/\mu s$
I_S	Supply Current	Per Amplifier			0.55		0.55		0.55		0.55		0.55	mA
			2		0.50		0.50		0.50		0.50		0.50	mA

Note 1: Guaranteed by design, characterization, or correlation to other tested parameters.

Note 2: Specification applies for $V_S^+ = 5V$, $V_S^- = 0V$, $V_{CM} = 0V$, $V_{OUT} = 1.4V$.

TABLE 2: ELECTRICAL TEST REQUIREMENTS

MIL-STD-883 TEST REQUIREMENTS	SUBGROUP
Final Electrical Test Requirements (Method 5004)	1*,2,3,4,5,6
Group A Test Requirements (Method 5005)	1,2,3,4,5,6
Group B and D for Class S	1,2,3
End Point Electrical Parameters (Method 5005)	

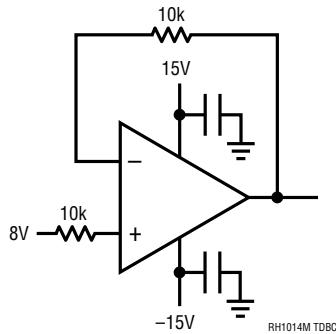
* PDA applies to subgroup 1. See PDA Test Notes.

PDA Test Notes

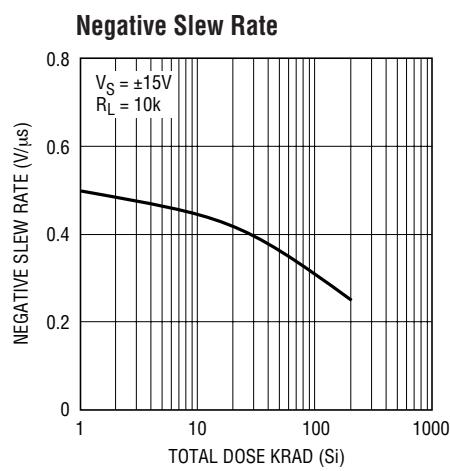
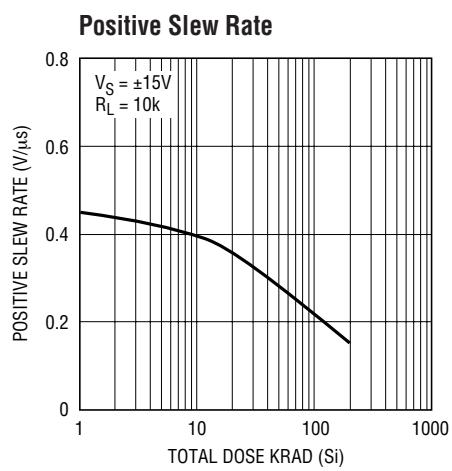
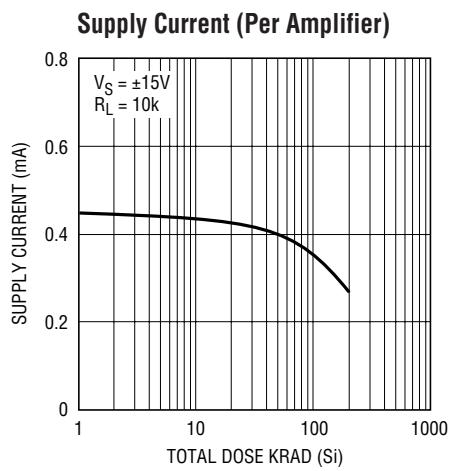
The PDA is specified as 5% based on failures from group A, subgroup 1, tests after cooldown as the final electrical test in accordance with method 5004 of MIL-STD-883. The verified failures of group A, subgroup 1, after burn-in divided by the total number of devices submitted for burn-in in that lot shall be used to determine the percent for the lot.

Linear Technology Corporation reserves the right to test to tighter limits than those given.

TOTAL DOSE BIAS CIRCUIT



TYPICAL PERFORMANCE CHARACTERISTICS



TYPICAL PERFORMANCE CHARACTERISTICS

